



IEC 61701:2011

Salt mist corrosion testing of photovoltaic (PV) modules

Confirmation of test results

Ref.: 10036/2021-40358

Applicant: LG Electronics Inc.
168, Suchul-daero, Gumi-si, Gyeongsangbuk-do,
730-903, South Korea

Product: Crystalline Silicon Photovoltaic (PV)-Modules

Type: A) LGXXN3C-V6
B) LGXXN3W-V6
C) LGXXN3K-V6

XXX in the type replace the power in Watt and can be any number between: 395 – 415 for A), B) and 390 – 410 for C)

Manufacturer: LG Electronics Inc.

Standard: IEC 61701:2011

Test conditions: As given in IEC 61701:2011

Severity: 6

Testing time: 56 days

Mist ph level: 7

Angle of inclination from horizontal: 75°

Pass criteria

Visual inspection: No findings which may affect safety.

Power degradation: < 5 %

Dry Insulation: > 40 MΩm²

Wet insulation: > 40 MΩm²

Bonding path resistance: < 0.1 Ω

Bypass diode functionality test: Bypass diodes shall remain functional



Summary of test results:

Visual inspection: No findings.

Maximum power degradation: allowed < 5 %
measured max. 1,21 %

The measured degradation is below the limit.

Dry insulation resistance: required $\geq 20,2 \text{ M}\Omega$
measured min. 999 $\text{M}\Omega$

The measured dry insulation resistance is above the limit.

Wet insulation resistance: required $\geq 20,2 \text{ M}\Omega$
measured min. 999 $\text{M}\Omega$

The measured wet insulation resistance is above the limit.

Bonding path resistance: required < 0,1 Ω
measured max. 0,0295 Ω

The measured bonding path resistance below the limit.

Bypass diode functionality test: Bypass diodes remain functional

The complete test results and the related bill of materials are given in the Test Report No. TRPVM-2021-40358-1.

VDE Renewables GmbH


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63755 Alzenau, 2021-05-28